

DOME GROUP

Dispositifs Opto et Microélectronique

L. BURGNIÉS, E. LHEURETTE, D. LIPPENS, X. MÉLIQUE, V. SADAUNE and O. VANBÉSIEAN

ELECTROMAGNETIC META-MATERIAL TECHNOLOGIES: FROM MICROWAVES TO OPTICS



Meta-Materials (MMs) @ Microwave/THz and infrared

Artificial Materials: Negative- and zero- positive index media by means of composite Right Left Handed (CRLH) metamaterial

Linear and non linear Devices: Negative Index Material (NIM) and Gradient Index (GRIN) lens, Phase shifter, tunable MMs, perfect metamaterial Absorbers (PMA)

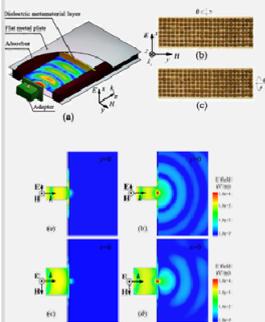
Systems: communications, spectroscopic and High Resolution (HR) imaging systems

Technologies: 2D and 2D1/2 surface and bulk technologies Transmission lines

Constitutive materials: Metallo-dielectric and Full dielectric structures based on conduction and displacement current loops

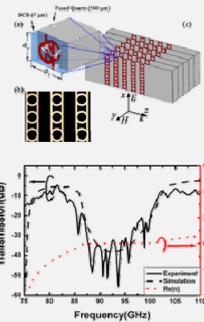
FULL DIELECTRIC AND METAL TECHNOLOGIES

Ferroelectric BST array



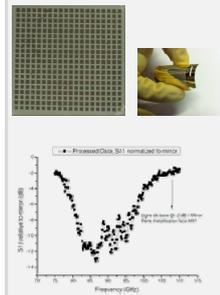
Extraordinary transmission

Split Ring resonator(SRR)



Negative index in V-band(50-75 GHz)

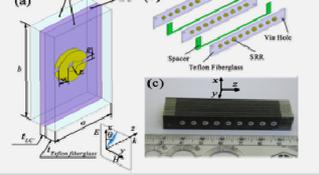
Perfect Metamaterial Absorbers flexible substrate



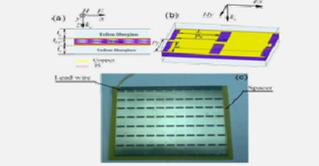
flexible substrate PMA

TUNABLE MMs BY LIQUID CRYSYAL (LC) AND FERROELECTRICS

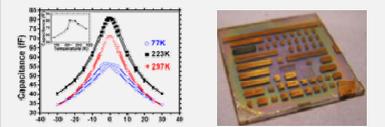
Broad side coupled SRR tuned with LC's



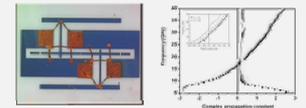
Fishnet-like tunable MMs



Ferroelectric BaSrTiO₃ CRLH transmission lines



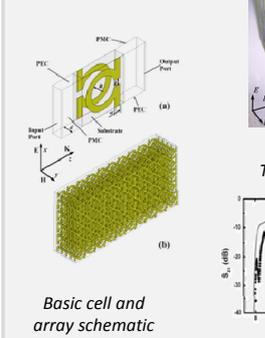
BST characterization at low temperatures



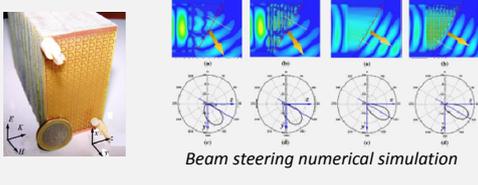
Monolithic fabrication and dispersion characteristics

BEAM STEERING VIA CRLH OMEGA-TYPE MMs

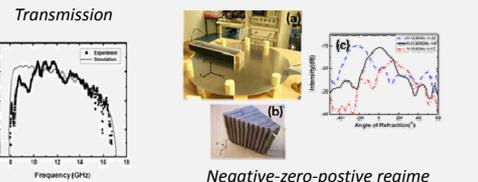
Omega type arrays



Basic cell and array schematic



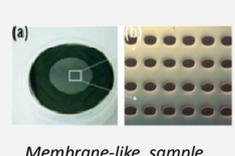
Beam steering numerical simulation



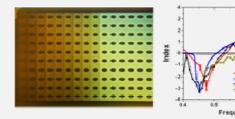
Negative-zero-positive regime (far field condition)

FISNET LIKE NIM AND CHIRAL MMs

Sub-wavelength hole arrays

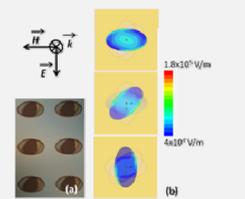


Membrane-like sample



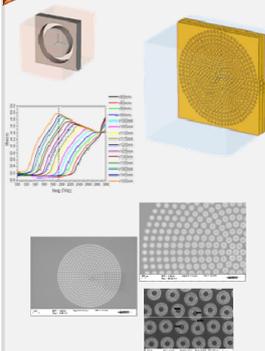
Wedge (type device) and refraction at 0.5 THz

Twisted hole structures

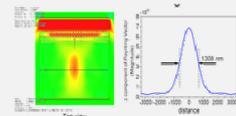


Rotary power as high as 100°/λ

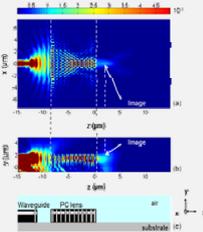
FOCUSING VIA NIM AND GRIN FLAT LENS



GRIN flat lens



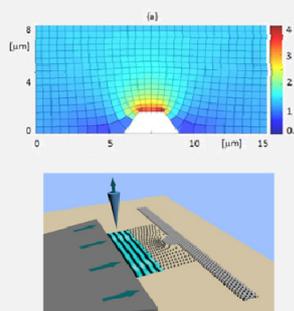
Negative Index flat lens



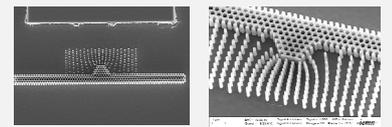
Metal technology

Semiconductor PC technology

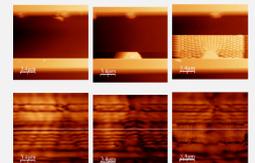
IMAGING AND STEATH SYSTEMS



Simulation by transformation optics



Photonic crystal (pillar-hole) technology



Scanning Near field Optical Microscopy